

Ongoing/New Radiation Evaluations for 2000.

- # *HIF Developments/Upgrades*
- # *PIF Developments/Upgrades (OPTIS)*
- # *FPGA – New Types (COO-2)*
Actel, Xilinx, Quick Logic,
Lattice, Lucent Technologies
- # *COTS:*
COO-1, NVRAMs Evaluation
COO-2, Support IC's



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Ref.: TOS-QCA-26/01/2000

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- # *Design of a Radiation Testbed for High Capacity Memory Components*
Contractor; IDA/DSS, (Germany)
- # *Utilisation of Pulsed Laser for SEE testing*
Contractor; Hirex/Matra BAe (F/UK)
- # *Radiation Characterisation and Test Methodology Study of Optocoupler Devices for Space Applications*
Contractor; MSS (France)
- # *Influence of the tilt Parameter during SEE Characterisation with Heavy Ion Beams*
Contractor; UCL (Belgium)



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Optocoupler Device Study:

Device Type	Version	Manufact.	Total Parts	Proton Test	Neutron Test	TID Co-60 LDR+HDR
4N49	Standard	Optek	70	25	15	15+15
4N49	Standard	Isolink	70	25	15	15+15
4N49	Standard	Micropac	70	25	15	15+15
66099	Hardened to displac ^t damage	Micropac	50	20	10	10+10
66168	Hardened to displac ^t damage	Micropac	70	25	15	15+15
6N140A	standard	HP	70	25	15	15+15
OLH249	Hardened to displac ^t damage	Isolink	50	20	10	10+10



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